

附表 3-2:

## 批准证书附件

Lab: Lab: Eurofins EAG Materials Sciences China

Add: Room 201, Building 2, No. 177 Jiangkai Road, Minhang, Shanghai, 201100, P.R. China

No.	Products, Materials	Items, Parameter		Title, Code of specification, standard or method used	Restriction or limitation	Measuring capacity	Note
		No.	Items, Parameter				
1	ESD & LATCH-UP CAPABILITY TEST FOR INTEGRATE CIRCUIT AND COMPONENT	1	Electrostatic Discharge Sensitivity Testing Human Body Model	ANSI/ESDA/JEDEC JS-001 (2023) Mil Std 883-K (2017) Method 3015.9 AEC Q100-002-E(2013) AEC-Q101-001-REV-A(2005)	HBM Restriction 0-4kV Limitation 8kV	768 channel	
		2	Electrostatic Discharge Sensitivity Testing Machine Model	JESD22-A115-C(2010) ESDA STM 5.2(2012)	MM Restriction 0-0.4kV Limitation 2kV	768 channel	
		3	Field-Induced Charge-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components	ANSI/ESDA/JEDEC JS-002 (2022) AEC Q100-011-REV-D(2019) AEC-Q101-005-REV-A(2019)	CDM Restriction 0-0.5kV Limitation 2kV	25.4mmx25.4mm	
		4	IC Latch-up Test	JESD78F.02(2023)	LATCH UP Restriction +/-100V,1A Limitation +/-30V,5A	768 channel	